

<b>Notice of References Cited</b>	Application/Control No. 09/656,315	Applicant(s)/Patent Under Reexamination SHIN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-5,297,278	03-1994	Wang et al.	707/200
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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